

Notice of References Cited	Application/Control No. 10/612,963	Applicant(s)/Patent Under Reexamination LO ET AL.	
	Examiner Thuy V. Tran	Art Unit 2821	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0227253 A1	12-2003	Seo et al.	313/504
	B	US-2003/0201727 A1	10-2003	Yamazaki et al.	315/169.1
	C	US-2002/0047550 A1	04-2002	Tanada, Yoshifumi	315/155
	D	US-6,777,886	08-2004	Lo et al.	315/169.1
	E	US-6,580,408	06-2003	Bae et al.	345/76
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.